2SK3637

Silicon N-channel power MOSFET

For PDP/For high-speed switching

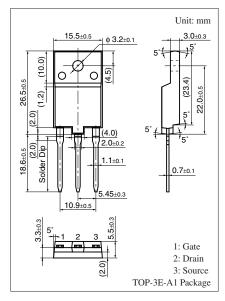
■ Features

- ullet Low on-resistance, low Q_g
- High avalanche resistance

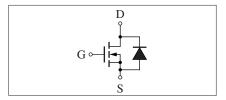
■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter		Symbol	Rating	Unit
Drain-source surrender voltage		V_{DSS}	200	V
Gate-source surrender voltage		V_{GSS}	±30	V
Drain current		I_D	50	A
Peak drain current		I_{DP}	200	A
Avalanche energy capability *		EAS	2000	mJ
Power		P_{D}	100	W
dissipation $T_a = 2$	25°C		3	
Channel temperature		T_{ch}	150	°C
Storage temperature		T_{stg}	-55 to +150	°C

Note) *: L = 0.8 mH, I_L = 50 A, V_{DD} = 100 V, 1 pulse, T_a = 25°C



Internal Connection



■ Electrical Characteristics $T_C = 25$ °C ± 3 °C

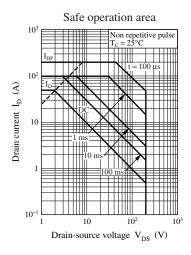
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Gate-drain surrender voltage	$V_{\rm DSS}$	$I_D = 1 \text{ mA}, V_{GS} = 0$	200			V
Diode forward voltage	V _{DSF}	$I_{DR} = 50 \text{ A}, V_{GS} = 0$			-1.5	V
Gate threshold voltage	V _{th}	$V_{DS} = 25 \text{ V}, I_{D} = 10 \text{ mA}$	2		4	V
Drain-source cutoff current	I_{DSS}	$V_{DS} = 160 \text{ V}, V_{GS} = 0$			100	μΑ
Gate-source cutoff currentt	I_{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0$			±1	μΑ
Drain-source on resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 25 \text{ A}$		29	40	mΩ
Forward transfer admittance	Y _{fs}	$V_{DS} = 25 \text{ V}, I_{D} = 25 \text{ A}$	15	30		S
Short-circuit forward transfer capacitance (Common-source)	C _{iss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		4550		pF
Short-circuit output capacitance (Common-source)	C _{oss}			750		pF
Reverse transfer capacitance (Common-source)	C _{rss}			75		pF
Turn-on delay time	t _{d(on)}	$V_{DD} = 100 \text{ V}, I_D = 25 \text{ A}$		50		ns
Rise time	t _r	$R_L = 4 \Omega$, $V_{GS} = 10 V$		125		ns
Turn-off delay time	t _{d(off)}			390		ns
Fall time	t _f			140		ns
Reverse recovery time	t _{rr}	$L = 230 \mu H, V_{DD} = 100 V$		210		ns
Reverse recovery charge	Q _{rr}	$I_{DR} = 25 \text{ A}, \text{ di /dt} = 100 \text{ A/ } \mu\text{s}$		820		nC

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

\blacksquare Electrical Characteristics (Continued) T_C = $25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Total gate charge	Qg	$V_{DD} = 100 \text{ V}, I_D = 25 \text{ A}$		85		nC
Gate-source charge	Qgs	$V_{GS} = 10 \text{ V}$		30		nC
Gate-drain charge	Q_{gd}			12		nC
Channel-case heat resistance	R _{th(ch-c)}				1.25	°C/W
Channel-atmosphere heat resistance	R _{th(ch-a)}				41.6	°C/W

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.



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